

FORM PTO-1449
(Equivalent)

U.S. Department of Commerce
Patent and Trademark Office

U.S. Application Serial No.
09/740,146

Atty. Docket No.
AM-3396.D1

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use several sheets if necessary)

Anisul Khan et al.
Applicants

December 18, 2000
Filing Date

1763
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U. S. PATENT DOCUMENTS

Examiner Initial	Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Gray</i>	5,431,772	07/11/95	Babie et al.	156	643.1	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Publication Date	Name	Class	Subclass	Translation If Appropriate
<i>Gray</i>	EP 0 854 510	07/22/98	Muller et al.	H01L	2178249	
<i>Gray</i>	JP 8017804	01/19/96	SONY CORP.	H01L	02073085	Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

Copy of a Search Report in corresponding EP Application No. EP 00120681.2-2203, dated September 22, 2002.

Examiner Date Considered

George Goudreau 9-031

Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U. S. PATENT DOCUMENTS

Examiner Initial	Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
	5,423,941 ✓	06/13/95	Komura et al.***	156	643.1	_____
	5,585,012 ✓	12/17/96	Wu et al.*	216	71	_____
	5,756,400 ✓	05/26/98	Ye et al.*	438	710	_____
	5,814,563 ✓	09/29/98	Ding et al.*	438	714	_____



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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Publication Date	Name	Class	Subclass	Translation If Appropriate
gag	WO 99/20812 ✓	04/29/99	Yin et al.**	23C	16741	_____
gag	WO 99/25,015 ✓	05/20/99	Qian Xue-Yu et al.****	H01L	21/5243	_____

Examiner Date Considered

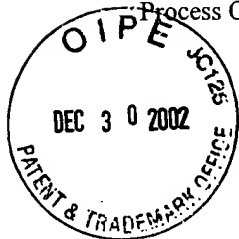
George Goudreau 9-031

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- * Provided by applicant in prosecution of parent application, U.S. Serial No. 09/405,349, as issued on November 20, 2001, U.S. Patent No. 6,318,384 B1.
- ** Cited by Examiner in prosecution of parent application, U.S. Serial No. 09/405,349, as issued on November 20, 2001, U.S. Patent No. 6,318,384 B1.
- *** Cited in a counterpart foreign application.
- **** Cited by Examiner in prosecution of parent application, U.S. Serial No. 09/405,349, as issued on November 20, 2001, U.S. Patent No. 6,318,384 B1. The Examiner has also cited EP 1,029,345 to Qian Xue-Yu et al., which has matured into WO 9925015. Therefore, EP 1,029,345 is not included as a reference.

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

Yan Ye et al., "0.35-Micron and Sub-0.35-Micron Metal Stack Etch in a DPS Chamber — DPS Chamber and Process Characterization," Electrochemical Society Proceedings, Vol. 96-12, (1996). pp. 222-233.



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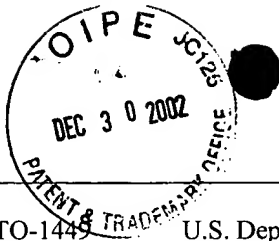
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<u>gmg</u>	4,376,672 ✓	03/15/83	Wang et al.*	156	643	_____
_____	4,668,338 ✓	05/26/87	Maydan et al.	156	643	_____
_____	4,842,683 ✓	06/27/89	Cheng et al.	156	345	_____
_____	4,951,601 ✓	08/28/90	Maydan et al.	118	719	_____
_____	5,186,594 ✓	02/16/93	Toshima et al.	414	217	_____
<u>gmg</u>	5,298,790 ✓	03/29/94	Harmon et al.***	257	622	_____

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